Product Preview

3 Channel Q1 BOOST **Module**

The NXH240B120H3Q1PG is a case power module containing a three channel BOOST stage. The integrated field stop trench IGBTs and SiC Diodes provide lower conduction losses and switching losses, enabling designers to achieve high efficiency and superior reliability.

Features

- 1200 V Ultra Field Stop IGBTs
- Low Reverse Recovery and Fast Switching SiC Diodes
- Low Inductive Layout
- Press-fit Pins
- Thermistor

Typical Applications

- Solar Inverters
- ESS

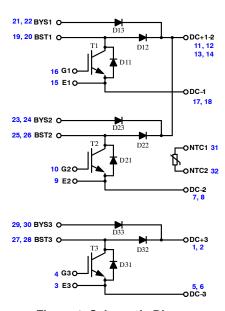


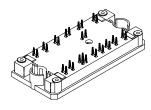
Figure 1. Schematic Diagram

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Q1BOOST CASE 180AX

MARKING DIAGRAM

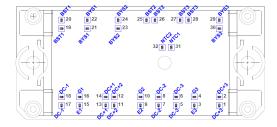


NXH240B120H3Q1PG = Specific Device Code

= Pb-Free Package

= Assembly & Test Site Code YYWW = Year and Work Week Code

PIN ASSIGNMENTS



ORDERING INFORMATION

See detailed ordering and shipping information in the dimensions section on page 13 of this data sheet.

Table 1. MAXIMUM RATINGS (Note 1)

Rating	Symbol	Value	Unit
GBT (T1, T2, T3)			
Collector-Emitter Voltage	V _{CES}	1200	V
Gate-Emitter Voltage	V _{GE}	±20	V
Continuous Collector Current @ T _h = 80°C (T _J = 175°C)	Ic	68	А
Pulsed Collector Current (T _J = 175°C)	I _{Cpulse}	204	А
Maximum Power Dissipation (T _J = 175°C)	P _{tot}	158	W
Minimum Operating Junction Temperature	T _{JMIN}	-40	°C
Maximum Operating Junction Temperature	T _{JMAX}	150	°C
PROTECTION DIODE (D11, D21, D31)	· · · · · · · · · · · · · · · · · · ·		
Peak Repetitive Reverse Voltage	V _{RRM}	1200	V
Continuous Forward Current @ T _h = 80°C (T _J = 150°C)	I _F	30	А
Repetitive Peak Forward Current (T _J = 150°C)	I _{FRM}	120	А
Maximum Power Dissipation (T _J = 150°C)	P _{tot}	44	W
Minimum Operating Junction Temperature	T _{JMIN}	-40	°C
Maximum Operating Junction Temperature	T _{JMAX}	150	°C
SILICON CARBIDE BOOST DIODE (D12, D22, D32)			•
Peak Repetitive Reverse Voltage	V _{RRM}	1200	V
Continuous Forward Current @ T _h = 80°C (T _J = 150°C)	I _F	22	А
Repetitive Peak Forward Current (T _J = 150°C)	I _{FRM}	66	А
Maximum Power Dissipation (T _J = 150°C)	P _{tot}	54	W
Minimum Operating Junction Temperature	T _{JMIN}	-40	°C
Maximum Operating Junction Temperature	T _{JMAX}	150	°C
BYPASS DIODE (D13, D23, D33)	· · · · · · · · · · · · · · · · · · ·		
Peak Repetitive Reverse Voltage	V_{RRM}	1200	V
Continuous Forward Current @ T _h = 80°C (T _J = 150°C)	I _F	42	А
Repetitive Peak Forward Current (T _J = 150°C)	I _{FRM}	126	А
Maximum Power Dissipation (T _J = 150°C)	P _{tot}	50	W
Minimum Operating Junction Temperature	T _{JMIN}	-40	°C
Maximum Operating Junction Temperature	T _{JMAX}	150	°C
THERMAL PROPERTIES	· · · · · ·		
Storage Temperature range	T _{stg}	-40 to 150	°C
NSULATION PROPERTIES			•
Isolation test voltage, t = 1 sec, 60 Hz	V _{is}	3000	V _{RMS}
Creepage distance		12.7	mm

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality

Table 2. RECOMMENDED OPERATING RANGES

Rating	Symbol	Min	Max	Unit
Module Operating Junction Temperature	TJ	-40	150	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

should not be assumed, damage may occur and reliability may be affected.

1. Refer to ELECTRICAL CHARACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe Operating parameters.

Table 3. ELECTRICAL CHARACTERISTICS T_J = 25°C unless otherwise noted

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
IGBT (T1, T2, T3)						
Collector-Emitter Cutoff Current	V _{GE} = 0 V, V _{CE} = 1200 V	I _{CES}	=	-	400	μΑ
Collector-Emitter Saturation Voltage	V _{GE} = 15 V, I _C = 80 A, T _J = 25°C	V _{CE(sat)}	=	1.65	2	V
	V _{GE} = 15 V, I _C = 80 A, T _J = 150°C		=	1.85	_	
Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}$, $I_C = 1.0 \text{ mA}$	V _{GE(TH)}	4.50	5.87	6.50	V
Gate Leakage Current	V _{GE} = 20 V, V _{CE} = 0 V	I _{GES}	=	-	800	nA
Turn-on Delay Time	T _J = 25°C	t _{d(on)}	=	13	_	ns
Rise Time	$V_{CE} = 800 \text{ V, } I_{C} = 50 \text{ A}$ $V_{GE} = +15 \text{ V, } -9 \text{ V, } R_{G} = 4.3 \Omega$	t _r	=	22	_	
Turn-off Delay Time	VGE = +13 V, -9 V, NG = 4.3 52	t _{d(off)}	-	262	_	
Fall Time	7	t _f	-	13	_	1
Turn-on Switching Loss per Pulse	7	E _{on}	_	1258	_	μЈ
Turn off Switching Loss per Pulse	7	E _{off}	_	1277	_	1
Turn-on Delay Time	T _J = 125°C	t _{d(on)}	_	32	_	ns
Rise Time	V_{CE} = 800 V, I_{C} = 50 A V_{GE} = +15 V, -9 V, R_{G} = 4.3 Ω	t _r	_	22	_	1
Turn-off Delay Time	V _{GE} = +15 V, −9 V, H _G = 4.3 Ω	t _{d(off)}	_	315	_	
Fall Time		t _f	_	22	_	1
Turn-on Switching Loss per Pulse	E _{on}	_	1306	_	μЈ	
Turn off Switching Loss per Pulse		E _{off}	=	2221	_	
Input Capacitance	V _{CE} = 20 V, V _{GE} = 0 V, f = 10 kHz	C _{ies}	=	18151	_	pF
Output Capacitance		C _{oes}	=	345	_	1
Reverse Transfer Capacitance		C _{res}	=	294	_	1
Total Gate Charge	$V_{CE} = 600 \text{ V}, I_{C} = 25 \text{ A}, V_{GE} = \pm 15 \text{ V}$	Qg	=	817	_	nC
Thermal Resistance - chip-to-heatsink	Thermal grease,	R _{thJH}	=	0.60	=	°C/W
Thermal Resistance - chip-to-case	Thickness = 2 Mil $\pm 2\%$, λ = 0.63 W/mK	R _{thJC}	=	0.29	_	°C/W
PROTECTION DIODE (D11, D21, D31)		•		•		•
Diode Forward Voltage	I _F = 30 A, T _J = 25°C	V _F	-	1.09	1.3	V
	I _F = 30 A, T _J = 150°C	-	=	0.99	_	1
Thermal Resistance - chip-to-heatsink	Thermal grease,	R _{thJH}	=	1.60	_	°C/W
Thermal Resistance - chip-to-case	Thickness = 2 Mil $\pm 2\%$, $\lambda = 0.63$ W/mK	R _{thJC}	=	0.98	_	°C/W
SILICON CARBIDE BOOST DIODE (D12,	D22, D32)				•	•
Diode Forward Voltage	I _F = 20 A, T _J = 25°C	V _F	=	1.48	1.75	V
	I _F = 20 A, T _J = 150°C		=	1.99	_	
Reverse Recovery Time	T _J = 25°C	t _{rr}	=	21	_	ns
Reverse Recovery Charge	$V_{CE} = 800 \text{ V}, I_{C} = 50 \text{ A}$	Q _{rr}	=	84	_	μC
Peak Reverse Recovery Current	V_{GE} = +15 V, -9 V, R_{G} = 4.3 Ω	I _{RRM}	=	7	_	Α
Peak Rate of Fall of Recovery Current		di/dt	=	1750	_	A/μs
Reverse Recovery Energy		E _{rr}	=	65	_	μJ
Reverse Recovery Time	T _J = 125°C	t _{rr}	=	22	_	ns
Reverse Recovery Charge	$V_{CE} = 800 \text{ V, } I_{C} = 50 \text{ A}$	Q _{rr}	=	89	_	μC
Peak Reverse Recovery Current	$V_{GE} = +15 \text{ V}, -9 \text{ V}, R_{G} = 4.3 \Omega$	I _{RRM}	_	8	_	A
Peak Rate of Fall of Recovery Current	1	di/dt	_	1800	_	A/μs
Reverse Recovery Energy	†	E _{rr}	_	99	_	μJ

Table 3. ELECTRICAL CHARACTERISTICS T_{.1} = 25°C unless otherwise noted

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
SILICON CARBIDE BOOST DIODE (D12,	D22, D32)					
Thermal Resistance - chip-to-heatsink	Thermal grease,	R_{thJH}	-	1.30	-	°C/W
Thermal Resistance - chip-to-case	Thickness = 2 Mil $\pm 2\%$, λ = 0.63 W/mK	R _{thJC}	-	0.85	-	°C/W
BYPASS DIODE (D13, D23, D33)						
Diode Forward Voltage	I _F = 50 A, T _J = 25°C	V_{F}	-	1.095	1.3	V
	I _F = 50 A, T _J = 150°C		-	1.004	-	_
Thermal Resistance - chip-to-heatsink	Thermal grease,	R_{thJH}	-	1.40	_	°C/W
Thermal Resistance - chip-to-case	Thickness = 2 Mil $\pm 2\%$, $\lambda = 0.63$ W/mK	R _{thJC}	_	0.85	-	°C/W
THERMISTOR CHARACTERISTICS						
Nominal resistance	T = 25°C	R ₂₅	-	5	-	kΩ
Nominal resistance $T = 100^{\circ}C$		R ₁₀₀	-	493.3	-	Ω
Deviation of R25		$\Delta R/R$	-5	-	5	%
Power dissipation		P_{D}	-	20	-	mW
Power dissipation constant			-	1.4	-	mW/K
B-value	B(25/50), tolerance ±2%		_	3375	-	K

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

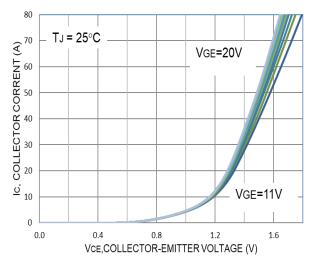
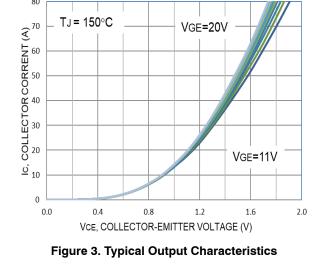


Figure 2. Typical Output Characteristics



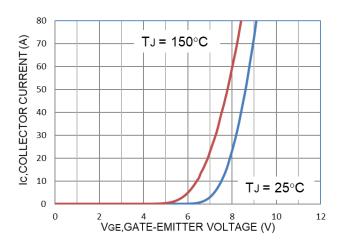


Figure 4. Typical Transfer Characteristics

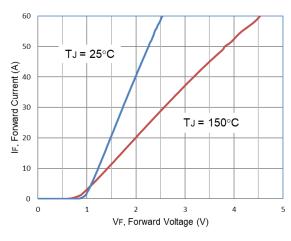


Figure 5. Diode Forward Characteristics

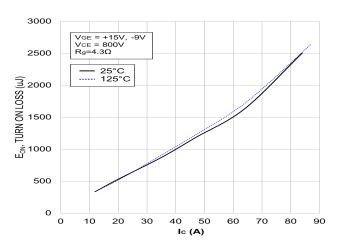


Figure 6. Typical Turn ON Loss vs. I_C

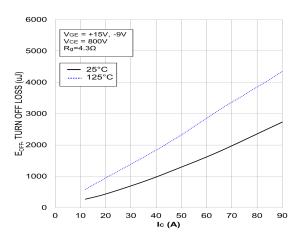


Figure 7. Typical Turn OFF Loss vs. I_C

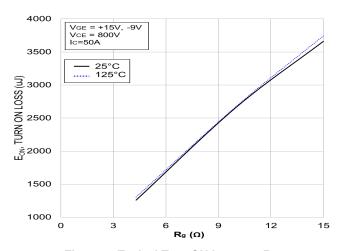


Figure 8. Typical Turn ON Loss vs. R_G

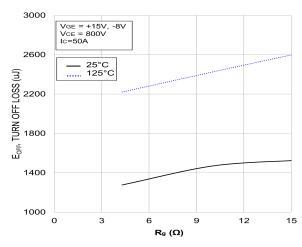


Figure 9. Typical Turn OFF Loss vs. R_G

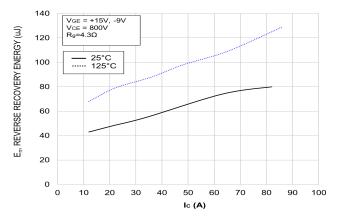


Figure 10. Typical Reverse Recovery Time vs. I_C

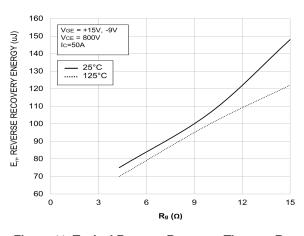


Figure 11. Typical Reverse Recovery Time vs. $R_{\mbox{\scriptsize G}}$

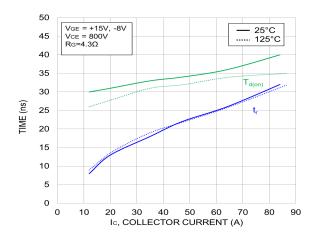


Figure 12. Typical Turn-On Switching Time vs. I_C

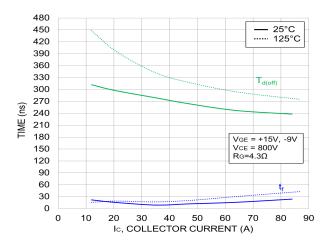


Figure 13. Typical Turn-Off Switching Time vs. I_C

TYPICAL CHARACTERISTICS - IGBT (T1, T2, T3) and Silicon Carbide Schottky Diode (D12, D22, D32)

800

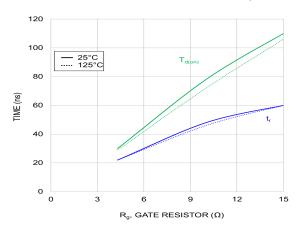
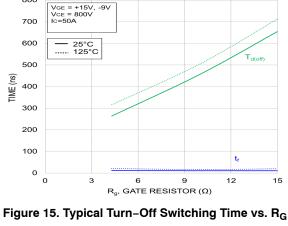


Figure 14. Typical Turn-On Switching Time vs. R_G



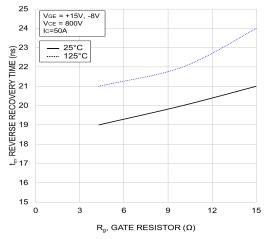


Figure 16. Typical Reverse Recovery Time vs. R_G

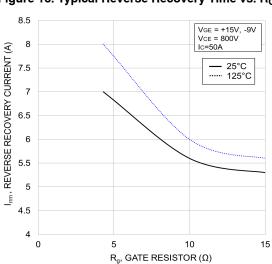


Figure 18. Typical Reverse Recovery Peak Current vs. R_G

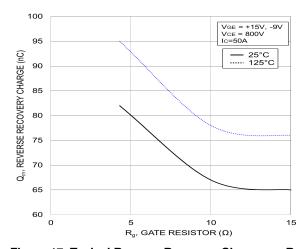


Figure 17. Typical Reverse Recovery Charge vs. R_G

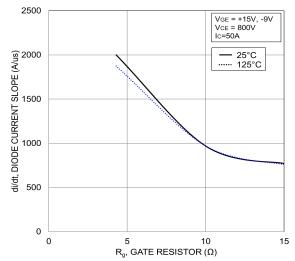


Figure 19. Typical di/dt vs. R_G

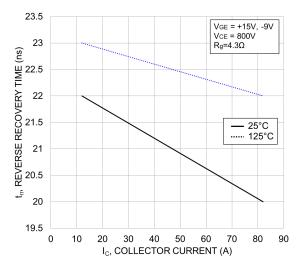


Figure 20. Typical Reverse Recovery Time vs. I_C

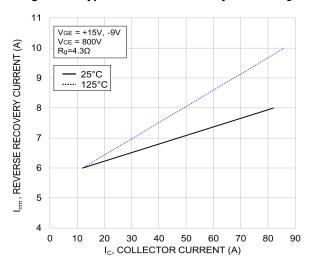


Figure 22. Typical Reverse Recovery Current vs. I_C

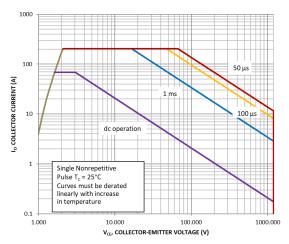


Figure 24. FBSOA

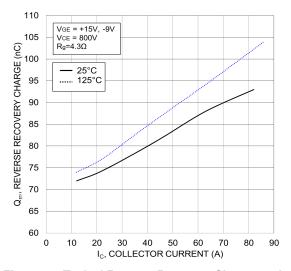


Figure 21. Typical Reverse Recovery Charge vs. I_C

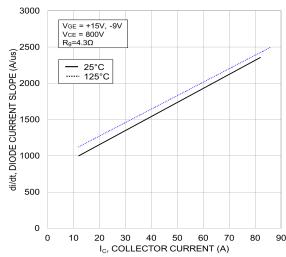


Figure 23. Typical di/dt Current Slope vs. I_C

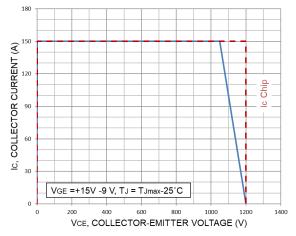


Figure 25. RBSOA

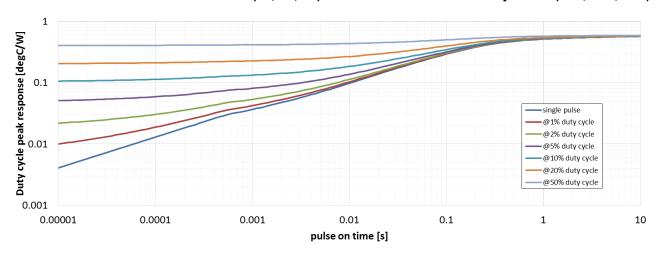


Figure 26. Transient Thermal Impedance (T1, T2, T3)

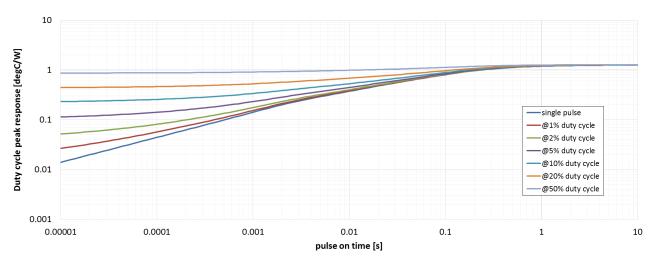


Figure 27. Transient Thermal Impedance (D12, D22, D32)

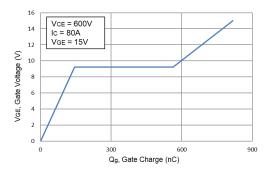


Figure 28. Gate Voltage vs. Gate Charge

TYPICAL CHARACTERISTICS - Diode (D13, D23, D33)

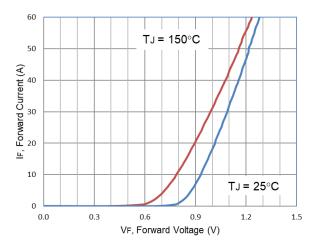


Figure 29. Diode Forward Characteristics

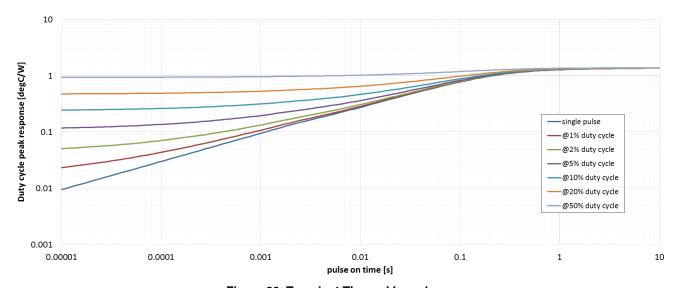


Figure 30. Transient Thermal Impedance

TYPICAL CHARACTERISTICS - Diode (D11, D21, D31)

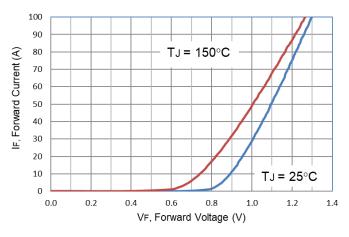


Figure 31. Diode Forward Characteristics

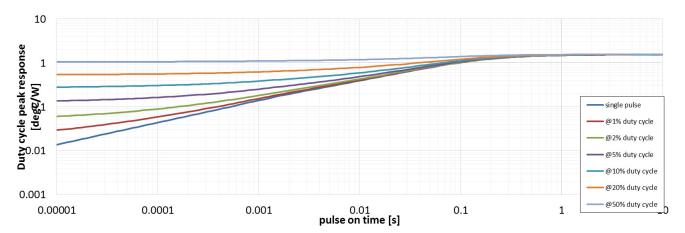


Figure 32. Transient Thermal Impedance

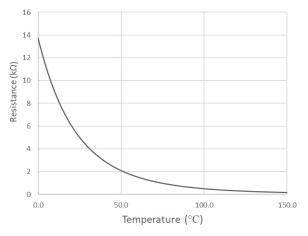
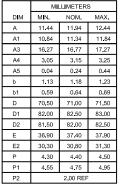


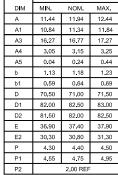
Figure 33. Thermistor Characteristic

PACKAGE DIMENSIONS

PIM32, 71x37.4 (PRESS-FIT) CASE 180AX ISSUE O

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. DIMENSIONS b AND b1 APPLY TO THE PLATED TERMINALS AND ARE MEASURED AT DIMENSION A4.
- 4. POSITION OF THE CENTER OF THE TERMINALS AND MOUNTING HOLES IS DETERMINED FROM DATUM B THE CENTER OF DIMENSION D, X DIRECTION, AND FROM DATUM A, Y DIRECTION. POSITIONAL TOLERANCE, AS NOTED IN DRAWING, APPLIES TO BOTH TERMINALS AND MOUNTING HOLES IN BOTH DIRECTIONS.
- 5. PACKAGE MARKING IS LOCATED, AS SHOWN, ON THE SIDE OPPOSITE THE PACKAGE ORIENTATION FEATRUES.
- 6. MOUNTING RECOMMENDATION IS SHOWN AS VIEWED FROM THE PCB TOP LAYER LOOKING DOWN TO SUBSEQUENT LAYERS.

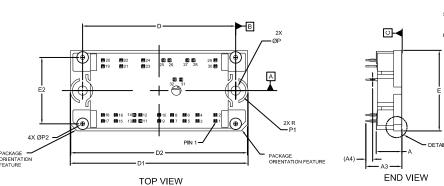






ତା≺ DETAIL A

	PIN POS	SITION		PIN POSITION		
PIN	Х	Υ	l	PIN	Х	Υ
1	26.10	-14.10		17	-26.10	-14.10
2	26.10	-11.30		18	-26.10	-11.30
3	17.80	-14.10	l	19	-26.10	11.30
4	17.80	-11.30		20	-26.10	14.10
5	11.80	-14.10	l	21	-17.60	11.30
6	11.80	-11.30		22	-17.60	14.10
7	6.00	-14.10	l	23	-7.40	11.30
8	6.00	-11.30		24	-7.40	14.10
9	0.00	-14.10	l	25	2.00	14.10
10	0.00	-11.30		26	4.80	14.10
11	-8.70	-14.10	l	○ ²⁷	13.10	14.10
12	-8.70	-11.30		28	15.90	14.10
13	-11.50	-14.10	l	29	26.10	14.10
14	-11.50	-11.30		30	26.10	11.30
15	-20.10	-14.10		31	10.20	5.10
16	-20.10	-11.30		32	7.20	5.10



NOTE 5 PACKAGE MARKING SIDE VIEW	DETAIL B
PLATED THRU HOLE 32X 01.09 19 021 023 024 19 021 023 024 28 28 27 28 310 0 0.00 0	OLE
RECOMMENDED	

MOUNTING PATTERN

Ф 0.80**©** С А В

ORDERING INFORMATION

Orderable Part Number	Marking	Package	Shipping
NXH240B120H3Q1PG	NXH240B120H3Q1PG	Q1 BOOST, Case 180AX Press-fit Pins (Pb-Free)	21 Units / Blister Tray

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